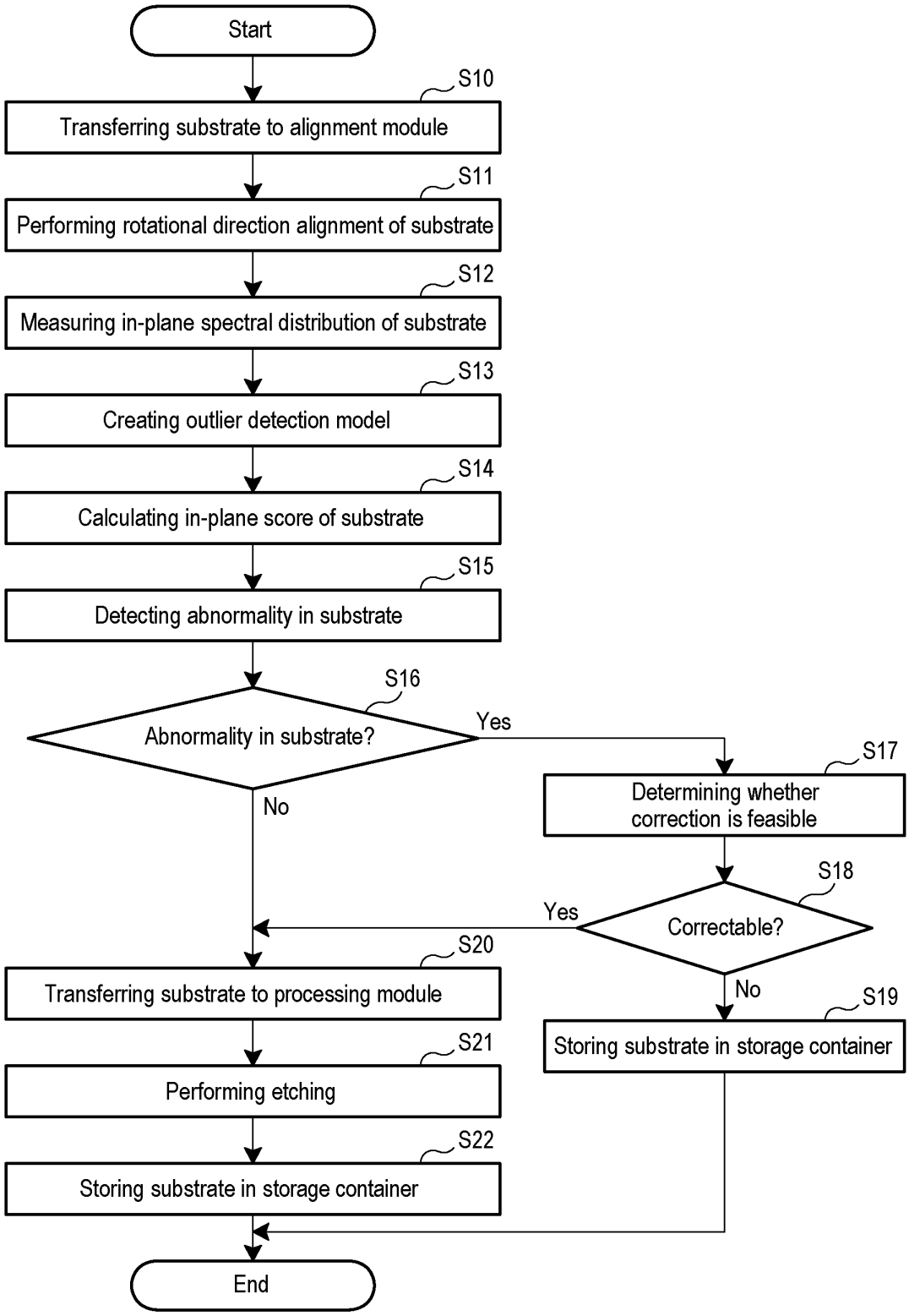
FIG. 12


Start
S10
Transferring substrate to alignment module
S11
Performing rotational direction alignment of substrate
S12
Measuring in-plane spectral distribution of substrate
S13
Creating outlier detection model
S14
Calculating in-plane score of substrate
S15
Detecting abnormality in substrate
S16
Abnormality in substrate?
Yes
No
S17
Determining whether correction is feasible
S18
Correctable?
Yes
No
S19
Storing substrate in storage container
S20
Transferring substrate to processing module
S21
Performing etching
S22
Storing substrate in storage container
End